Optical Measurement Technology and Instrument

http://www.csoe.org.cn/IPTA2016/

May 9-11, 2016

China National Convention Center (CNCC), Beijing China

Registration:  http://events.kjtxw.com/register/1426492992.html

Sponsor:
Chinese Society for Optical Engineering (CSOE)

Technical-sponsor:
The International Society of Optics and Photonics (SPIE)
Optical Society of America (OSA)

Organizer:
Chinese Society for Optical Engineering (CSOE)

Co-organizer:
Precision Engineering sub-Society of China Instrument and Control Society (PES/CIS)
Beijing Jiaotong University (BJU)

Conference Chairs:

Sen Han (University of Shanghai for Science and Technology, China)

Virendra N. Mahajan (University of Arizona, USA)

Jiubin Tan (Harbin Institute of Technology, China)
Technical Committee:
Qing Ran (National Institute of Measurement and Testing Technology, China)
Zuobin Wang (Changchun University of Science and Technology, China)
Yongjun Xie (Xi’an Institute of Optics and Fine Mechanics, CAS, China)
Yingjie Yu (Shanghai University, China)
Jianqiang Zhu (Shanghai Institute of Optics and Fine Mechanics, CAS, China)

Topics: (Not limited in the fields)
- Testing and alignment of optical surfaces and systems
- Test for super-precision optical surface
- Test for freeform optics
- Measurement for super smooth surface
- Measurement of optical thin film
- Test of infrared technologies
- Optical test and measurement for Micro and Nano scale technology
- Laser radar
- Modern Optoelectronic Instruments
- Detectors Focal Plane Instrumentation
- IR/X-ray/UV measurement technology and Instrument
- Measurement Uncertainty and Machine Tool Testing
- Measurement of Radiometry and photometry
- Measurement of 3D Imaging and Display

Invited Talks: (updating)
- Wilfried Bauer (Polytec GmbH, Germany) —— Combination of White Light Interferometers with Vision Control for the Characterization of Functional Surfaces in Quality Control
- Ludger Koenders (Physikalisch-Technische Bundesanstalt, Germany) —— Surface Metrology at the Micro and NanoScale – Techniques, Standards for Dimensional and areal roughness at its limits
- Virendra N. Mahajan (University of Arizona, USA) —— Common Mistakes, Misusage, and other Observations in Aberrated Imaging/ Some Interesting Topics Related to Defocus Aberration
- Yuki Shimizu (Tohoku University, Japan) —— Investigation on the Sensitivity of an Optical Angle Sensor Based on Laser Autocollimation
- Ching-Cherng Sun (National Central University, Taiwan) —— Detection of phosphor temperature for phosphor-converted white LEDs
- Weichang Xie (University of Kassel, Germany) —— Influences of Edges and Steep Slopes in 3D Interference and Confocal Microscopy
- Xipeng Zhang (Unice E-O Services Inc., USA) —— Interferometric Optical Testing of a Five Feet Diagonal Fresnel Lens for QC Purposes
- Qibo Feng (Beijing Jiaotong University, China) —— System for Simultaneously Measuring 6DOF Geometric Motion Errors Using Fiber-coupled Laser
- Cheng Liu (Shanghai Institute of Optics and Fine Mechanics, CAS, China) —— Coded Split Method for the Wave-front Measurement
Shiyuan Liu (Huazhong University of Science and Technology, China) —— Mueller Matrix Ellipsometry for Nanostructured Surface Metrology

Dapeng Qu (Changchun New Industries Optoelectronics Tech. Co., Ltd. (CNI), China) —— Laser in Optogenetics

Jianda Shao (Shanghai Institute of Optics and Fine Mechanics, CAS, China) —— Large Optics Metrology for SG-series Laser Facility

Jiubin Tan (Harbin Institute of Technology, China) —— TBD

Shouhong Tang (Suzhou H&L Instruments LLC., China) —— Digitized Interferometry and its Applications

Yingjie Yu (Shanghai University, China) —— Measuring Cylindricity Error Using Stitching Interferometry

Xiaodong Yuan (China Academy of Engineering Physics, China) —— Research on the Precision Assembly System for SG-III Laser Facility

Xiaori Zhang (Shanghai Raising Measurement Technology, China) —— Laser Based Guiding Techniques and Its Applications in Shield Construction

Weiqian Zhao (Beijing Institute of Technology, China) —— Laser Differential Confocal Imaging / Measurement Technique and Its Instrumentation Research Progress

Weihu Zhou (Academy of Opto-electronics, CAS, China) —— Research of Laser Tracker Based on Femtosecond Frequency Comb Technology

**Short Course:**

Sen Han (University of Shanghai for Science and Technology, China)

Virendra N. Mahajan (University of Arizona, USA)

**Title 1:** Some interesting topics related to defocus aberration

**Title 2:** Wavefront Analysis

**Secretaries:**

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The Program Committee of OTA
Chinese Society for Optical Engineering (CSOE)
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